

<b>Notice of References Cited</b>	Application/Control No. 10/607,524		Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner Diane Yabut		Art Unit 3734	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,187,019	02-2001	Stefanchik et al.	606/144
*	B	US-6,036,700	03-2000	Stefanchik et al.	606/144
*	C	US-6,200,263	03-2001	Person, Wayne C.	600/227
*	D	US-2002/0095166	07-2002	Vargas et al.	606/150
*	E	US-2001/0023353	09-2001	VARGAS et al.	606/153
*	F	US-6,530,932	03-2003	Swayze et al.	606/144
*	G	US-6,394,948	05-2002	Borst et al.	600/37
*	H	US-4,318,313	03-1982	Tartaglia, John A.	294/99.2
*	I	US-6,821,286	11-2004	Carranza et al.	606/153
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.